

**Workshop Time:**

Sunday May 21<sup>st</sup> 9:00 AM to 11:00 AM

**Workshop Title:**

“Using Visual Data Mining for More Effective Patent Analysis”

**Workshop Instructors:**

- Dr. Jeffrey D. Saffer, President, OmniViz, Inc.
- Dr. Philip J. Monroe, Senior Director Technology Applications, OmniViz, Inc.
- Dr. Vicki L. Burnett, Senior Director Technology Applications, OmniViz, Inc.

**Workshop Abstract:**

This workshop is designed to help prospective users understand the value of OmniViz’s visual data mining as well as to provide current users with tips and approaches to help in their analyses. The workshop will begin with an overview of the basics of visual data mining – what it is, when to use it, and how it can decrease risk and improve productivity in your patent analyses. In addition, the approaches in the OmniViz software will be compared and contrasted to other methods. This introduction will be followed by a demonstration of how to be more effective in competitive assessment using the visual methods available within the OmniViz software. Finally, a demonstration of using visual data mining for defining freedom to operate and to identify potential infringements will be provided. Together these demonstrations will enable patent analysts to better understand how and when to make use of the OmniViz software. Throughout the demonstrations, the new features in the latest version of the OmniViz software will be highlighted.

**OmniViz website and logo:**

[www.omniviz.com](http://www.omniviz.com)

**Workshop Registration:**

Send email to: [PIUGworkshop@omniviz.com](mailto:PIUGworkshop@omniviz.com)

Please include your name, organization, and number registering.

**For questions contact:**

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